COMING EVENTS

1996 Microwave Workshop Series. (Ted) Pella, Inc.) Kathy Stangerberg (800)637-3526 (CA), (800)237-3526 (except CA)

July 1/3 '96: Hamilton, MT Aug 7/9 '96: Madison, WI

CCD Imaging Workshops (Photometrics) 1 Tucson, AZ. Lisa Soroka: (520)889-9933, Fax: (520)295-0299.

Oct 3/4 '96

 First Wed, of Each Month in '96: New Strategies & Tactics in Image Analysis. Iowa City, IA. Dr. J.K. Beddow, (319)337-2427, Fax: (319)337-2474.

July 14/19 '96: 43rd International Field Emission Symposium. Moscow, Russia. Prof. A.L. Suvorov: eMail: suvorov@cl.itep.ru

July 21/24 '96: 29th Annual International Metallographic Society Conference. Pittsburgh, PA. Dr. M.G. Burke: (412)476-5883.

July 22/25 '96: INTER/MICRO-96. (McCrone Research Institute) Chicago, IL. Nancy Daerr: (312)842-7100, Fax: (312)842-1078

✓ July 27/August 4 '96: 3D Microscopy of Living Cells (Univ. of British Columbia). Vancouver, BC, Canada. Dr. James Pawley: (608)263-3147, Fax: (608)265-5315, eMail: JPAWLEY@macc.wisc.edu

✓ August 2/3 '96: 47 Annual Meeting of the Histochemical Society. Bethesda, MD. (508)563-1155, Fax: (508)563-1211.

✓ August 3/8 '96: 45th Annual Denver X-ray Conference and Powder Diffraction Satellite Meeting, Denver, CO

✓ August 8/17 '96: 17th Congress and General Assembly of the International Union for Crystallography. Seattle, WA. Prof. R.F. Bryan, http://www.hwi.bufallo.edu/aca/

1 August 11/15 '96: MSA/MAS/MSC Joint Annual Meeting, Minneapolis, MN MSA Business Office: (508)540-5594/(800)538-3672, Fax: (508)548-9053.

August 26/30 '96; EUREM '96, University 1 College, Dublin, Ireland. Prof. Martin Steer: 353-1-7062254 Fax: 353-1-7061153

Sept 4/7 '96: Surfaces in Biomaterials '96. Phoenix, AZ. (612)927-6707, Fax: (612)927-8127.

Sept 18/21 '96: Gold Cluster Labeling Workshop. Brookhaven Nat'l Lab, Upton, NY. Jim Hainfeld, (516)344-3372, Fax: (516)344-3407

Sept 20/22 '96: Symposium on Integrated 1 Microscopy (Univ. of Wisconsin & Carnegie-Mellon Univ.) Madsion, WI: eMail: http://www.bocklabs.wisc.edu/imr/imr.html

Sept 26/Oct 2 '98: 14th International EM Congress. Cancun, Mexico. Miguel Jose Yacaman: Tel./Fax: 525-570-85-03

Sept 30/Oct 4 '96: OIM Academy: Course in Orientation Imaging Microscopy. (TSL), Provo, UT. Klaus Behnert: (801)344-8990, Fax: (801)344-8997

Oct 1/4 '96: Ultramicrotomy for Materials 1 Science Applications Workshop. (RMC & AZ Materials Lab). Tucson, AZ. Dr. Bob Chiovetti: (520)889-7900, Fax: (520)741-2200.

✓ Oct 7/11 '96: Scanning Electron Microscopy and X-Ray Microanalysis for the Materials Scientists. (SUNY). New Paltz, NY. Dr. A.V. Patsis: (914)255-0757, Fax: (914)255-0978.

✓ Oct 13/16 '96: 5th Brazilian Conference on Microscopy of Materials - MICROMAT 96: Rio de Janeiro. Secretariat: Fax: 55-21-5112182, eMail: sbme@rdc.puc-rio.br

✓ Oct 14/18 '96: 43rd American Vacuum Society National Symposium. Philadelphia, PA. (212)248-0200, Fax: (212)248-0245

Dec. 2/6 '96: Symposium on Materials 1 Issues in Art and Archaeology V. (Smithsonian Inst.) Boston, MA, Pamela Vandiver: (301)238-3700, Fax: (301)238-3709.

Dec. 4/6 '96: 26th Annual Conference of 1 the Microscopy Society of Southern Africa. Durban, South Africa Dr. Fiona Graham, +27-31-260-2174, Fax: +27-31-261-6550.

✓ February 8/14 '97: Photonics West '97. (SPIE). San Jose, CA. Marilyn Gorsuch: (360)676-3290, Fax: (360)647-1445.

February 24/28 '97: LIM Academy: 1 Course in Orientation Imaging Microscopy. (TSL). Klaus Behnert: (801)344-8990, Fax: (801)344-8997/

March 16/21 '97: PITTCON '97 - Atlanta. GA. (412)825-3220, Fax: (412)825-3224.

✓ June 9/14 '97: ACHEM 97 - International Meeting on Chemical Engineering, Environmental Protection and Biotechnology. Frankfurt am Main. +49(69)7564-280, Fax: +49(69)7564-201.



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